

Workshop Schedule – May 17th

MORNING SESSION	
Oral presentations	
Session Chair:	Yuval Garini, Bar-Ilan University, Israel
10:00 - 10:10	<i>Greetings</i>
10:10 - 10:50	Yafit Fleger, Bar-Ilan University, Israel <i>Taking Ga FIB to the Limit</i>
10:50 - 11:30	Gregor Hlawacek, Helmholtz-Zentrum Dresden-Rossendorf, Dresden, Germany <i>Applications of Helium Ion Microscopy</i>
11:30 - 11:45	Coffee Break
11:45 - 12:25	Katya Rechav, Weizmann Institute of Science, Israel <i>FIB-SEM Techniques for Biology: Exploring the Depths</i>
12:30 - 13:30	Lunch
AFTERNOON SESSION	
Companies Presentations	
Session Chair:	Zahava Barkay, Tel-Aviv University, Israel
13:30 – 13:55	Vítězslav Ambrož, Tescan Orsay Holding, Brno, Czech Republic <i>FIB/SEM Technology for Advanced Nanofabrication and In Situ Analysis</i>
13:55 - 14:20	Andreas Schertel, Carl Zeiss Microscopy GmbH, Oberkochen, Germany <i>Volume Imaging of Cellular Ultrastructure in Native Frozen Biological Samples by Using Cryo-FIB-SEM</i>
14:20 - 14:45	Daniel Phifer, FEI Company, Eindhoven, The Netherlands <i>Fast, Flexible Sample Preparation with DualBeam™ Instruments</i>
14:45 - 15:00	Coffee Break
Hands-On Workshop	
15:00 – 17:00	<ul style="list-style-type: none"> • Ga Ion FIB • He/N Ion FIB • Ion Beam Analyzer • Cryo TEM (+ sample preparation) • High Resolution TEM
17:00	Departure